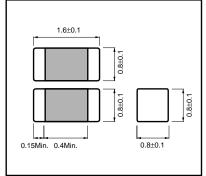
Multi-layer ceramic chip capacitors

MCH18 (1608 (0603) size, chip capacitor)

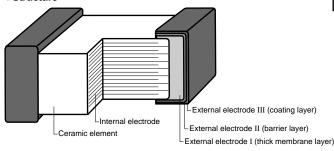
Features

- 1) Small size (1.6 x 0.8 x 0.8 mm) makes it perfect for lightweight portable devices.
- 2) Comes packed either in tape to enable automatic mounting or in bulk cases.
- 3) Precise uniformity of shape and dimentions highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.

●External dimensions (Units : mm)



Structure



(-55~+125)

-25~+85

FN

Product designation

Part

M

							1	(0.8mm	Paper ta	ape (width 8 mm, pitch 4 mm)	\phi180mm (7in.)	4,000
			L	_ 0.8mm	Paper ta	ape (width 8 mm, pitch 4 mm)	ф330mm (13in.)	16,000				
								0.8mm		Bulk case	_	15,000
	Ree I(\(\phi\)180.\(\phi\)330mm): compatible with EIAJ ET-7200A											
- (N) -								k case :compatible		EIAJ E1-7201A		
rt No.				_			<u> Pa</u>	ckaging styl	le			
		-										
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ΛШ	C	∥н	ı	1	∥ ନ	2 F	N 1 0	4 7	ΙL	(
′⊔∟												
_											•	
Rated voltage Capacitance-temperature characteristics				e characteristics	Nominal	Cap	acitance tolerance	l				
Co	de	Voltage		Code	Code	Operating temperature (°C)	Temp. coefficient or percent change	capacitance	Code	tolerance		
7	2	25V		Α	CG(C0G)	-55~+125	±30ppm/°C		С	±0.25pF (0.5 ~ 5pF)	1	
3	3	16V		CN	R	-55~+125	±15%		D	±0.5pF (5.1 ~ 10pF)	1	
	5	50V			В	-25~+85	±10%	3-digit designation	J	±5% (11pF or more)	1	
	_								_			

Code Product thickness Packaging specifications

*The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

(±15%)

+30%,-80%

ROHM

●Capacitance range

For thermal compensation

Part nui	MCH18			
Canacitanas(»F)	Temperature characteristics	A (CG) (C0G)		
Capacitance(pF)	Rated voltage	50		
	Tolerance (V)			
0.5				
0.75 1				
1.1		××××		
1.2		××××		
1.3		*****		
1.5 1.6				
1.8				
2		*****		
2.2	C (± 0.25pF)			
2.4				
2.7 3				
3.3				
3.6		****		
3.9 4				
4.3	-	××××		
4.7				
5				
5.1				
5.6 6				
6.2		××××		
6.8		*****		
7	D (± 0.5pF)			
7.5 8				
8.2		×××××		
9		****		
9.1		××××		
10		×××××		
11 12				
13				
15		×××		
16 18		×××××		
20	-			
22		******		
24				
27		**************************************		
30 33				
36	J (±5%)	XXXX		
39				
43				
47 51				
56				
62	1	*****		
68 75				
75 82	-			
82 91				
100				

Part nur	MCH18	
	Temperature characteristics	A (CG) (C0G)
Capacitance (pF)	Rated voltage Tolerance (V)	50
110		
120		******
130		******
150		******
160		******
180		******
200		*****
220		
240		
270		******
300	J (± 5%)	******
330		*****
360		
390		
430		
470		******
510		
560		
620		*****
680		
750		
820		******
910		
1,000		

Product thickness (mm) 0.8 ± 0.1

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

High dielectric constant

Part num	nber	MCH18					
Capacitance(pF)	Temperature characteristics	CN (R) (B) (X7R)		FN (F) (Y5V)			
Сараснансе(рг)	Rated voltage (V)	50	25	50	25	16	
	Tolerance	K (±10%)		Z (+80%, -20%)		%)	
220		*****					
270 330		****					
390 470 560		*****					
680 820 1,000							
1,200 1,500 1,800		×××					
2,200 2,700 3,300							
3,900 4,700 5,600				****			
6,800 8,200 10,000 (0.01μF)				****			
12,000 15,000 18,000		****					
22,000 27,000 33,000			****				
39,000 47,000 56,000			****	****			
68,000 82,000					×××		
100,000 (0.1μF) 120,000 150,000 180,000			XXXXXX		XXXXXX		
220,000 270,000 330,000							
390,000 470,000 560,000							
680,000 1,000,000 (1μF) 1,200,000							
1,500,000 1,800,000 2,200,000							

Product thickness (mm) 0.8 ± 0.1

*The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



Characteristics

Class 1 (For thermal compensation)

Item	Temperature characteristics	A (CG) (C0G)	Test methods / conditions (based on JIS C 5102)		
Operating temp	perature	−55°C ~ +125°C			
Nominal capac	itance (C)	Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humid 1000pF or less Measurement frequency: 1± 0.1Mh		
Dissipation fact	tor (tan δ)	100 / (400 + 20C)% or less (Less than 30 pF) 0.1% or less (30 pF or larger)	Measurement voltage : 1± 0.1Vrm Over 1000pF Measurement frequency : 1± 0.1kHz Measurement voltage : 1± 0.1Vrm		
Insulation resis	stance (IR)	10,000MΩ or $500 M\Omega \cdot \mu F$, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 ± 5s.		
Withstanding v	oltage	The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.		
Temperature cl	haracteristics	Within 0 \pm 30ppm / °C	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.		
Terminal adher	rence	No detachment or signs of detachment.	Based on paragraph 8.11.2 Apply 5N for $10 \pm 1s$ in the direction indicated by the arrow.		
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the manner shown on the right, subjected to vibration (type A in paragraph 8.2),		
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.			
	Dissipation factor (tanδ)	Must satisfy initial specified value.	and measured 24 ± 2 hrs. later. Board		
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature : $235 \pm 5^{\circ}$ C Soldering time : 2 ± 0.5 s		
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	$\pm2.5\%$ or ±0.25 pF , whichever is larger.	Based on paragraph 8.14		
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.	Soldering temperature : 260 ± 5°C Soldering time : 5 ± 0.5s		
heat	Insulation resistance	10,000MΩ or 500MΩ·μF , whichever is smaller	Preheating : 150 ± 10°C for 1 to 2 min.		
	Withstanding voltage	The insulation must not be damaged.	1 10 2 11111.		
	Appearance	There must be no mechanical damage.			
Temperature	Rate of capacitance change	$\pm~2.5\%\pm0.25~\text{pF}$, whichever is larger.	Based on paragraph 9.3		
cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.	Number of cycles : 5 Capacitance measured after 24 ± 2		
	Insulation resistance	10,000MΩ or 500MΩ·μF , whichever is smaller	1		
	Appearance	There must be no mechanical damage.	Based on paragraph 9.9		
Humidity load	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF , whichever is larger.	Test temperature : 40 ± 2°C Relative humidity : 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.		
test	Dissipation factor (tanδ)	0.5% or less			
	Insulation resistance	500MΩ or 25MΩ·μF , whichever is smaller	Capacitance measured after 24 ± 2 hrs		
	Appearance	There must be no mechanical damage.	Based on paragraph 9.10 Test temperature : Max. operating te Applied voltage : rated voltage × 2t Test time : 1,000 to 1,048 hr.		
High-	Rate of capacitance change	$\pm~3.0\%$ or $\pm~0.3~\text{pF}$, whichever is larger.			
temperature load test	Dissipation factor (tanδ)	0.3% or less			
	Insulation resistance	1,000M Ω or 50M Ω ·μF , whichever is smaller	Capacitance measured after 24 ± 2 h		

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Class 2 (High dielectric constant)

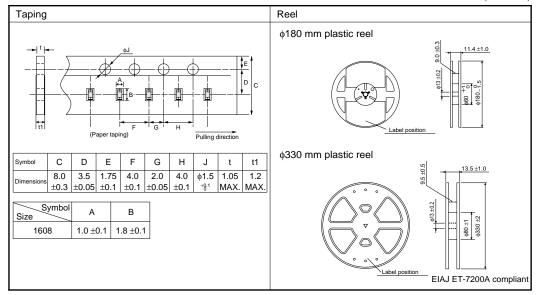
Jiass 2 (High diei	iedino donstanti)					
Item	Temperature characteristics	CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)		
Operating temp	perature	-55°C ~ +125°C	-30°C ~ +85°C			
Nominal capaci	itance (C)	Must be within the spe	Based on paragraph 7.8 Measured at room temperature and standard humidity Measurement frequency: 1 ± 0.1 kHz Measurement voltage : 1.0 ± 0.2 Vrms.			
Dissipation factor	or (tanδ)	2.5% or less (when rated voltage is 16V: 3.5% or less)				
Insulation resist	tance (IR)	10,000 MΩ or 500 MΩ -	Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$.			
Withstanding vo	oltage	The insulation mus	Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measure			
Temperature ch	haracteristics	Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20°C , with no voltage applied.		
Terminal adher	rence	No detachment or s	Based on paragraph 8. 11. 2. Apply 5N for 10 ± 1s in the direction indicated by the arrow.			
	Appearance	There must be no m	nechanical damage.	Chip is mounted to a board in the		
Resistance to vibration	Rate of capacitance change	Must be within i	manner shown on the right, subjected to vibration (type A in paragraph 8.2),			
	Dissipation factor ($tan\delta$)	Must satisfy initia	Il specified value.	and measured 48 ± 4 hrs. later. Board		
Solderability		At least 3/4 of the surface of the two terr	Based on paragraph 8. 13 Soldering temperature: $235 \pm 5^{\circ}\text{C}$ Soldering time $: 2 \pm 0.5\text{s}$			
	Appearance	There must be no m	nechanical damage.			
	Rate of capacitance change	Within ± 5.0%	Within ± 20.0%	Deced on personal 0 44		
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initia	Il specified value.	Based on paragraph 8. 14. Soldering temperature: 260 ± 5°C		
heat	Insulation resistance	10,000MΩ or 500MΩ · μF, whichever is smaller		$ \begin{array}{lll} \mbox{Soldering time} & : 5 \pm 0.5 \mbox{s} \\ \mbox{Preheating} & : 150 \pm 10^{\circ}\mbox{C for} \\ \mbox{1 to 2 min.} \\ \end{array} $		
	Withstanding voltage	The insulation mus				
	Appearance	There must be no m	nechanical damage.			
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3 Number of cycles : 5		
cycling	Dissipation factor (tanδ)	Must satisfy initia	Il specified value.	Capacitance measured after 48 ± 4 h		
	Insulation resistance	10,000MΩ or 500MΩ · μ				
	Appearance	There must be no m	nechanical damage.	Based on paragraph 9.9		
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature: 40 ± 2°C		
Humidity load test	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.		
	Insulation resistance	500M Ω or 25M Ω · μF	Capacitance measured after 48 ± 4 h			
	Appearance	There must be no m	nechanical damage.			
Ī	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10		
High- temperature load test	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Test temperature: Max. operating temp. Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.		
load tost				Capacitance measured after 48 ± 4		

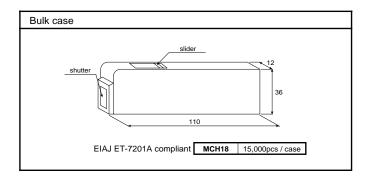
^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



Packaging specifications

(Units : mm)





^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

Electrical characteristics

■ A (C0G) Characteristics

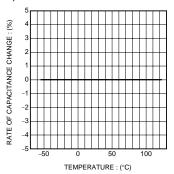


Fig.1 Capacitance - temperature characteristics

Fig.2 Impedance - frequency characteristics

■CN (X7R) Characteristics

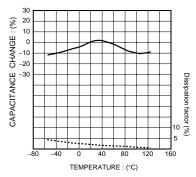


Fig.3 Capacitance - temperature characteristics

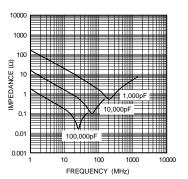


Fig.4 Impedance - frequency characteristics

■FN (Y5V) Characteristics

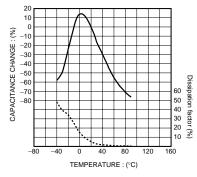


Fig.5 Capacitance - temperature characteristics

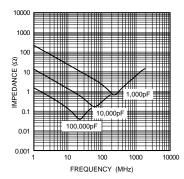
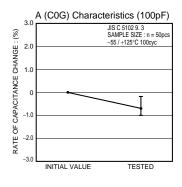


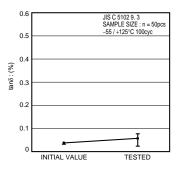
Fig.6 Impedance - frequency characteristics

ROHM

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ Temperature cycling test





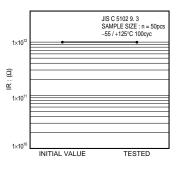
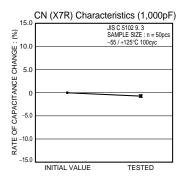
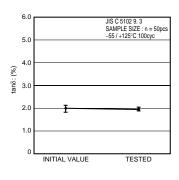


Fig.7 Rate of capacitance change

Fig.8 tanδ

Fig.9 Insulation resistance





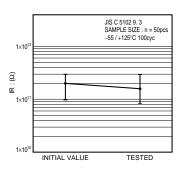
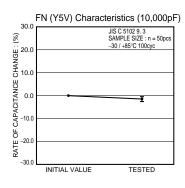
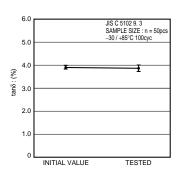


Fig.10 Rate of capacitance change

Fig.11 tanδ

Fig.12 Insulation resistance





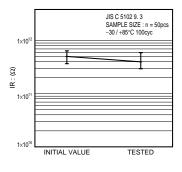


Fig.13 Rate of capacitance change

Fig.14 tanδ

Fig.15 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ High-temperature load test

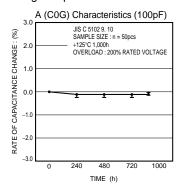


Fig.16 Rate of capacitance change

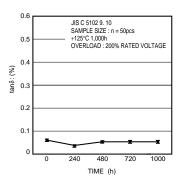


Fig.17 tanδ

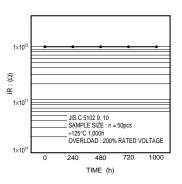


Fig.18 Insulation resistance

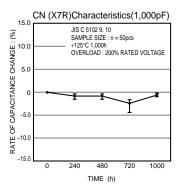


Fig.19 Rate of capacitance change

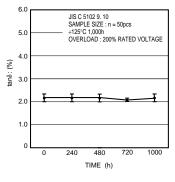


Fig.20 $\tan \delta$

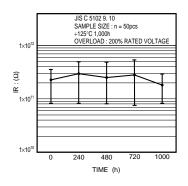


Fig.21 Insulation resistance

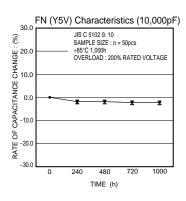


Fig.22 Rate of capacitance change

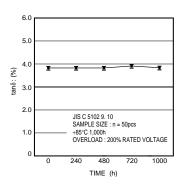


Fig.23 $tan\delta$

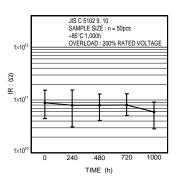
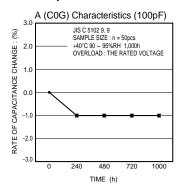
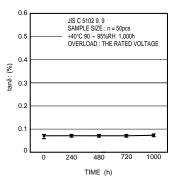


Fig.24 Insulation resistance

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■ Humidity load test





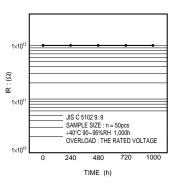
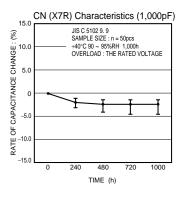
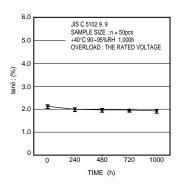


Fig.25 Rate of capacitance change

Fig.26 $tan \delta$

Fig.27 Insulation resistance





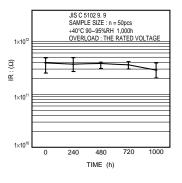
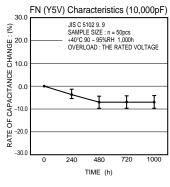
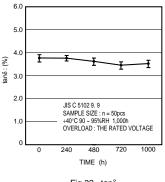


Fig.28 Rate of capacitance change

Fig.29 $tan\delta$

Fig.30 Insulation resistance





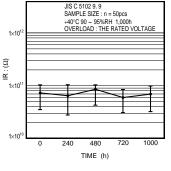


Fig.31 Rate of capacitance change

Fig.32 tanδ

Fig.33 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

